

Session Program

22-26 May 2017



**5th International Conference on
Micro-Pattern Gas Detectors (MPGD2017) and RD51 Collaboration Meeting**
Temple University, Philadelphia, USA
May 22-26, 2017



Meeting Home Page: <https://phys.cst.temple.edu/mpgd2017/>

May 22 - 25, 2017: MPGD2017 Conference – May 26, 2017: RD51 Collaboration Meeting

5th International Conference on Micro-Pattern Gas Detectors (MPGD2017)

Coffee Break and Poster Session - 1

Temple University - Philadelphia, Morgan Hall D301
Morgan Hall, 1398 Cecil B. Moore Ave., Philadelphia, PA 19122, USA

Monday 22 May

15:00

Coffee Break and Poster Session - 1

Session |

Location: Temple University - Philadelphia, Morgan Hall D301, Morgan Hall, 1398 Cecil B. Moore Ave., Philadelphia, PA 19122, USA

15:00-15:04 **How many electrons can fit in a GEM hole?**

Speaker

Piotr Gasik

15:04-15:08

Radiation studies on resistive bulk-micromegas chambers at the CERN Gamma Irradiation Facility

Speaker

Jerome Samarati

15:08-15:12

Characterization of Micromegas detector with elongated pillars

Speaker

Ourania Sidiropoulou

15:12-15:16

Characteristics of Micromegas detectors at high temperature

Speaker

Luigi Longo

15:16-15:20

VMM3, an ASIC for Micropattern Detectors

Speaker

George Iakovidis

15:20-15:24

Level-1 Data Driver Card - A high bandwidth radiation tolerant aggregator board for detectors

Speaker

Panagiotis Gkountoumis

15:24-15:28

Imaging with glass GEM and dynamic time-over-threshold pulse processing method

Speaker

Yuki Mitsuya

15:28-15:32

A new self-stretching method for large size GEM assembly

Speaker

Yi Zhou

15:32-15:36

A model of charge transfer processes in GEM foils

Speaker

Viktor Ratza

15:36-15:40

The importance of LAr TPC in neutrino experiments.

Speakers

Rafael M. Gutiérrez, Maritza Delgado

15:40-15:44

A photoelectric-effect-based field calibration system for the Time Projection Chamber at the CBELSA/TAPS experiment

Speaker

Dimitri Schaab

15:44-15:48

GEM based alternatives for ion backflow suppression

Speakers

Purba Battacharya, Marcelo Gameiro Munhoz

15:48-15:52

The GEM stability test against frequent high voltage on and off switching.

Speaker

Sonoe Oda

16:00